## Notice of References Cited Application/Control No. 10/608,093 Applicant(s)/Patent Under Reexamination WATANABE ET AL. Examiner TRUNG DIEP Applicant(s)/Patent Under Reexamination WATANABE ET AL. Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,646,677 B2	11-2003	Noro et al.	348/156
*	В	US-6,356,303 B1	03-2002	Shibata et al.	348/211.1
*	С	US-6,961,082 B2	11-2005	Miura et al.	348/211.9
*	D	US-6,313,875 B1	11-2001	Suga et al.	348/211.99
	Е	US-			
	F	US-			
	G	US-			
	Н	US-		7	
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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	Р		A			
	Q					
9	R					
	s					
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## NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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